NSN 5962-01-356-9317

Memory Microcircuit - Page 1 of 1



View Online at https://aerobasegroup.com/nsn/5962-01-356-9317

Features Provided:
Electrostatic sensitive and monolithic
Inclosure Configuration:
Dual-in-line
Output Logic Form:
Complementary-metal oxide-semiconductor logic
Product Name:
Electrically programmable rom
Memory Device Type:
Prom
Test Data Document:
96906-mil-std-883 standard (includes industry or association standards, individual manufactureer standards, etc.).
Shelf Life:
N/a
Unit Of Measure:

Demilitarization:
Yes - demil/mli
Fiig:
A458a0